

Sequential Test Planning for Polymer Composites

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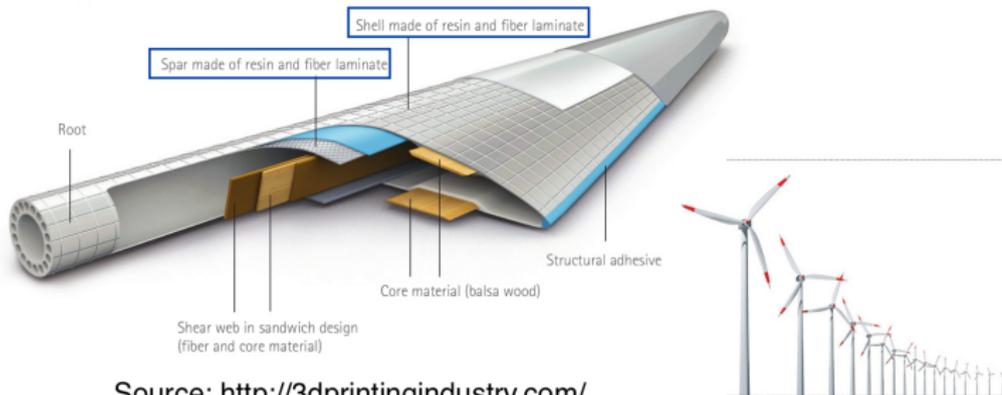
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Outline

- 1 Background and Introduction
- 2 Fatigue Data and Model
- 3 Test Planning Methodology
- 4 Sequential Testing and Comparison
- 5 Conclusion and Future Research

Polymer composites

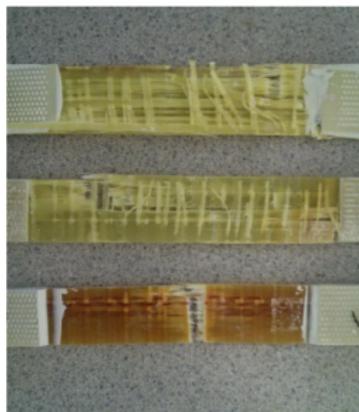
- A composite is any material made of more than one component with different physical or chemical properties.
- Polymer composites are made from polymers or from polymers along with other kinds of materials.
- Light weight, high strength, and long-term durability
- Wind turbine blades and aircraft are usually made of polymer composites.



Source: <http://3dprintingindustry.com/>

Fatigue tests for polymer composites

- The majority of testing is in accordance with the current standards provided in ASTM E739.
- The most common form of fatigue testing is cyclic constant amplitude fatigue testing.
- Fatigue occurs when the material is subject to varying levels of stress over a period of time.



Constant amplitude fatigue testing



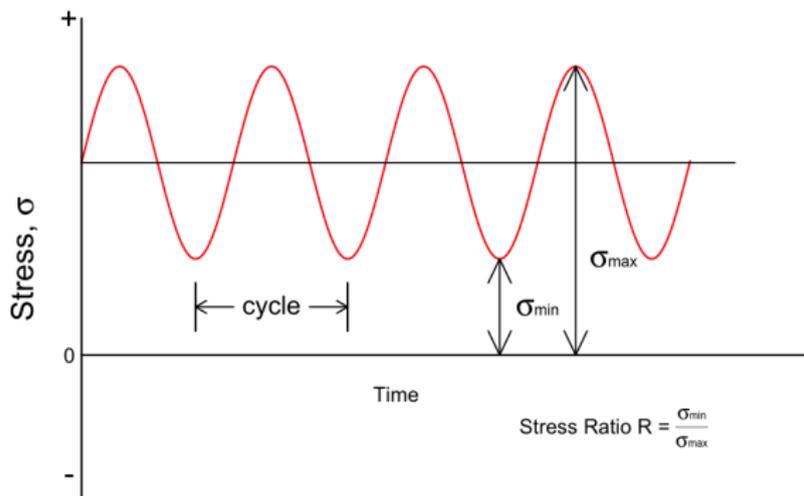
$\alpha = 0^\circ$
0° ply



$\alpha = +45^\circ$
+45° ply



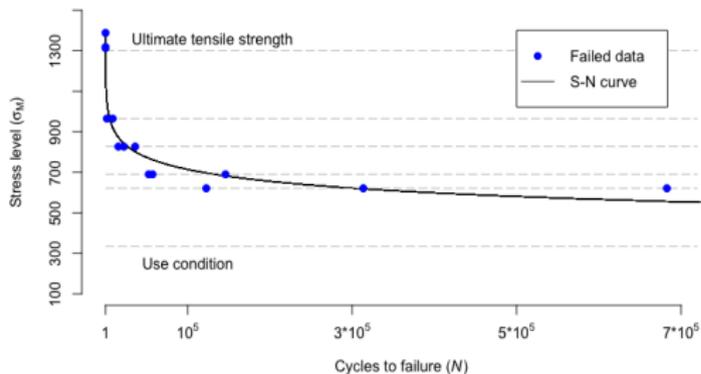
$\alpha = 90^\circ$
90° ply



Objective

- One main goal of fatigue test is to demonstrate that a p proportion of the materials can last a certain number of cycles under the use stress level.
- It is related to the prediction of the quantile of the cycles to failure distribution at use condition.
- The objective of this talk is to develop a sequential test planning strategy to polymer composites fatigue testing.

Relationship between cycles and stress levels



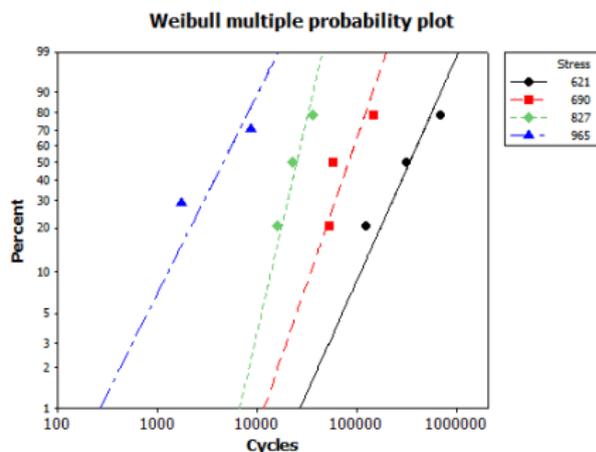
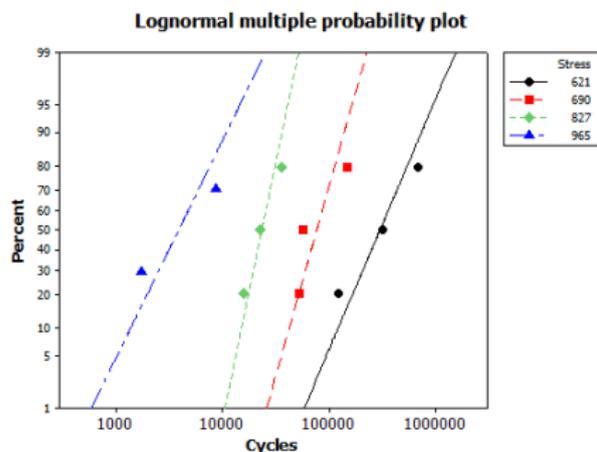
- Three samples are tested for ultimate tensile strength σ_U .
- Four stress levels are used.
- S-N curve is fitted by an empirical model in Epaarachchi and Clausen(2003).

Epaarachchi and Clausen (2003) proposed the relationship as

$$N(\sigma_M) = \frac{1}{B} \log \left\{ 1 + \left(\frac{B}{A} \right) f^B \left(\frac{\sigma_u}{\sigma_M} - 1 \right) \left(\frac{\sigma_u}{\sigma_M} \right)^{\gamma(\alpha)-1} [1 - \psi(R)]^{-\gamma(\alpha)} \right\}.$$

- A is environmental effects on the material fatigue.
- B is effects from the material itself.
- σ_M and σ_m are the maximum and minimum strength during the test.
- f is the frequency of the cyclic testing.
- $\psi(R) = \begin{cases} R & -\infty < R < 1 \\ \frac{1}{R} & 1 < R < \infty \end{cases}$, where $R = \sigma_m/\sigma_M$.
- $\gamma(\alpha) = 1.6 - \psi |\sin(\alpha)|$ is a function of the smallest angle α .

Statistical model for cycles to failure



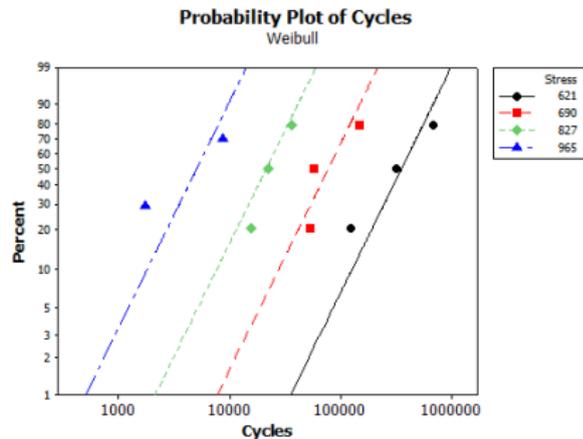
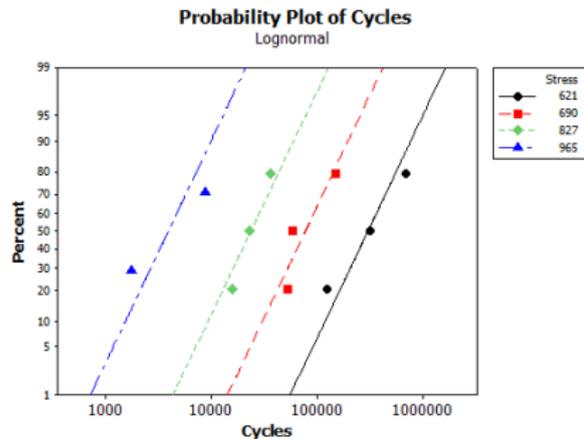
Assume the fatigue data are generated from the log-location-scale family of distributions, e.g., lognormal and the Weibull distribution.

Statistical model for cycles to failure

- The log-location-scale family is used to describe the cycles to failure (T_i). That is,

$$F(t_i) = \Phi \left(\frac{\log(t_i) - \mu_{\sigma_{M_i}}(A, B)}{\nu} \right).$$

- The location parameter is $\mu_{\sigma_{M_i}}(A, B) = N(\sigma_{M_i})$.
- The scale parameter is ν .
- The unknown parameters are $\theta = (A, B, \nu)$.



- The likelihood function is

$$L(\theta|data) = \prod_{i=1}^n \left[\frac{1}{\nu t_i} \phi \left(\frac{\log(t_i) - \mu_{\sigma_{M_i}}(A, B)}{\nu} \right) \right]^{(1-\delta_i)} \\ \times \left[1 - \Phi \left(\frac{\log(t_i) - \mu_{\sigma_{M_i}}(A, B)}{\nu} \right) \right]^{\delta_i},$$

where δ_i is the censoring indicator.

- The log-likelihood function is

$$l(\theta|data) = \sum_{i=1}^n (1 - \delta_i) [-\log \nu - \log t_i + \log \phi(z_i)] + \delta_i \log [1 - \Phi(z_i)],$$

where $z_i = [\log(t_i) - \mu_{\sigma_{M_i}}(A, B)]/\nu$.

- The Fisher information matrix is

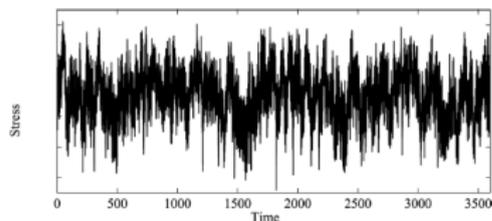
$$I(\boldsymbol{\theta}) = \mathbb{E} \left[-\frac{\partial^2 l(\boldsymbol{\theta})}{\partial \boldsymbol{\theta} \partial \boldsymbol{\theta}'} \right].$$

- The estimator of logarithm of the p quantile at stress s is $\log(\hat{\xi}_{p,s}) = \mu_s(\hat{A}, \hat{B}) + z_p \hat{\nu}$, where \hat{A} , \hat{B} , and $\hat{\nu}$ are estimators of A , B , and ν .
- The large-sample asymptotic variance of $\log(\hat{\xi}_{p,u_k})$ at use condition u_k is derived as

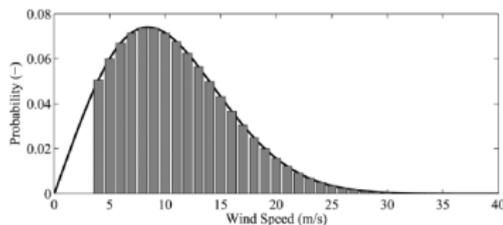
$$\text{AVar} \left\{ \log(\hat{\xi}_{p,u_k}) \right\} = \mathbf{c}_k \boldsymbol{\Sigma}_\theta \mathbf{c}_k',$$

where $\mathbf{c}_k = \left[\frac{\partial \mu_{u_k}(A,B)}{\partial A}, \frac{\partial \mu_{u_k}(A,B)}{\partial B}, z_p \right]$ and $\boldsymbol{\Sigma}_\theta = I^{-1}(\boldsymbol{\theta})$.

Distribution profile of use stress levels



Wind Turbine Blade Stress



Wind Speed Distribution

The weighted sum of the large-sample asymptotic variance of the estimator of the p quantile of the lifetime distribution at a vector of specified use levels can be expressed as

$$\text{AVar} \left\{ \log \left(\hat{\xi}_{p, use} \right) \right\} = \sum_{k=1}^K w_k \text{AVar} \left\{ \log \left(\hat{\xi}_{p, u_k} \right) \right\},$$

where w_k is the weight of the use level u_k and $\sum_{k=1}^K w_k = 1$.

- Stress level
 - A fatigue test contains S stress levels.
 - Let $q_i = \sigma_{M_i} / \sigma_u$ and subject to $q_i \in [q_L, q_U]$, where $i = 1, \dots, S$, q_L and q_U are the lower and upper bounds for stress levels.
- King et al. (2016) have discussed the optimum design on fatigue testings for composite material.
 - The results are obtained by minimizing $A\text{Var} \left\{ \log \left(\hat{\xi}_{p,use} \right) \right\}$ under the assumption that values of true parameters are known.
 - The optimum design always ends up with a lower and a higher stress levels.

- Traditional optimum designs
 - Depending on values of parameters
 - Assume true values of parameters are known
 - Treat maximum likelihood (ML) estimators as the true values
 - Unreliable inference based on ML estimators for small sample size
- Limits of experiments
 - Experiments are time-consuming and costly
 - The number of samples can be tested at a time are limited



- (Sequential) Bayesian designs
 - Allow prior knowledge to be used in design
 - Deal with difficulties of traditional optimum designs
 - D-optimality (Dror and Steinberg, 2008; Roy et al., 2009; Zhu et al., 2014)

Bayesian test planning

- Bayesian D-optimality design (Chaloner and Verdinelli, 1995):

$$\eta^* = \arg \max_{\eta} \int_{\Theta} \log \det (I(\theta, \eta)) \pi(\theta) d\theta,$$

- η is all possible designs, η^* is the optimum design.
 - $I(\theta, \eta)$ is the Fisher information matrix of θ for the design η .
 - $\pi(\theta)$ is the prior distribution of θ .
- Sequential Bayesian D-optimality design (Roy et al., 2009):

$$q_{D,n+1}^* = \arg \max_q \int_{\Theta} \log \det \left(\sum_{i=1}^n I(\theta, q_i) + I(\theta, q) \right) \pi(\theta | \mathbf{q}_n, \mathbf{t}_n) d\theta.$$

- $I(\theta, q)$ is the Fisher information matrix for the stress level q .
- $\pi(\theta | \mathbf{q}_n, \mathbf{t}_n)$ is the posterior distribution for θ given currently available data.

- For reliability analysts, it is important to obtain a precise prediction of a product's lifetime.
- The objective function is written as

$$\phi_n(q) = \int_{\Theta} V(q, \theta) \pi(\theta | \mathbf{q}_n, \mathbf{t}_n) d\theta,$$

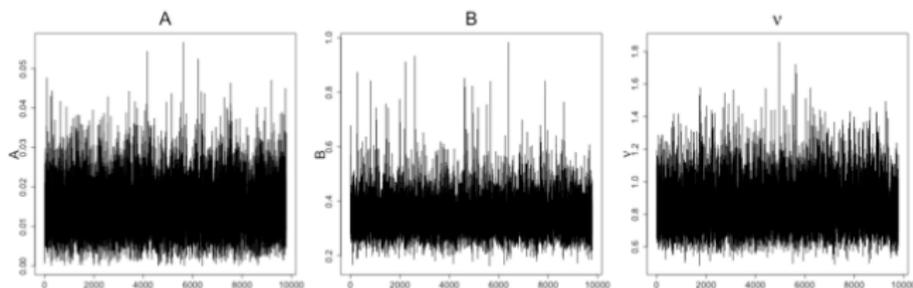
where $V(q, \theta) = \left[\sum_{k=1}^K w_k \mathbf{c}_k \Sigma_{\theta}(q) \mathbf{c}_k^T \right]$ and
 $\Sigma_{\theta}(q) = \left[\sum_{i=1}^n I(\theta, q_i) + I(\theta, q) \right]^{-1}$.

- The optimum $(n+1)^{th}$ design is

$$q_{C,n+1}^* = \arg \min_{q \in [q_m, q_M]} \phi_n(q).$$

Algorithm

Step 1: MCMC draws, $\theta_n^{(j)}$, based on n observations (current data)



Step 2: evaluate the asymptotic variance of each draw for possible designs

Possible design (q)	$\theta_n^{(1)}$...	$\theta_n^{(J)}$	Average
q_L	$V(q_L, \theta_n^{(1)})$...	$V(q_L, \theta_n^{(J)})$	$\phi_n(q_L)$
\vdots	\vdots	...	\vdots	\vdots
q_U	$V(q_U, \theta_n^{(1)})$...	$V(q_U, \theta_n^{(J)})$	$\phi_n(q_U)$

$$q_{C,n+1}^* = \arg \min \{ \phi_n(q_L), \dots, \phi_n(q_U) \}$$

Step 3: Add a new lifetime data under stress level $q_{C,n+1}^*$ from true distribution into current data

Example revisited

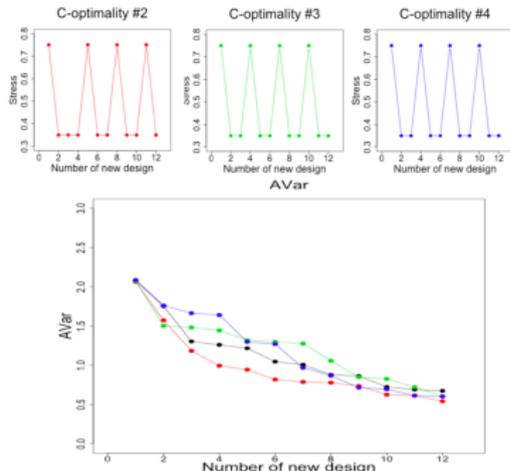
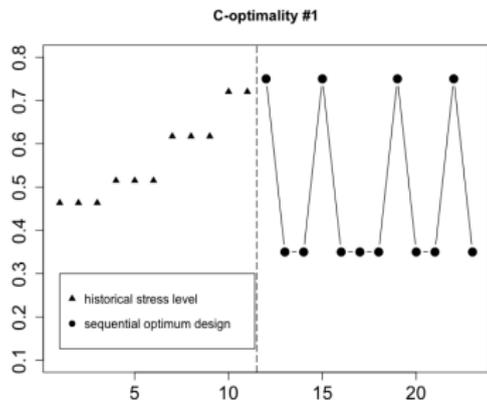
- The controlled settings are $R = 0.1$, $\alpha = 0$, and $\sigma_u = 1339.67$ MPa.
- Epaarachchi and Clausen (2003) provided the fitted values of A and B for different materials under different experimental settings.
- Assume the prior distributions are $A \sim \text{Unif}(0, 0.1)$, $B \sim \text{Unif}(0, 1)$, and $\nu^2 \sim \text{Inv.Gamma}(4.5, 3)$.
- MCMC method and the Metropolis-Hastings algorithm are used to simulate the Markov chains.

	\hat{A}	\hat{B}	$\hat{\nu}$
ML estimators	0.0157	0.3188	0.7259
Bayesian estimators	0.0145	0.3444	0.8413

- True values of parameters are set as $\hat{\theta}_0 = (0.0157, 0.3188, 0.7259)$.

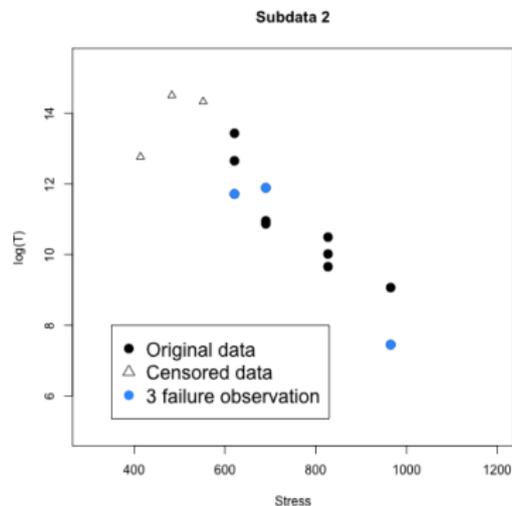
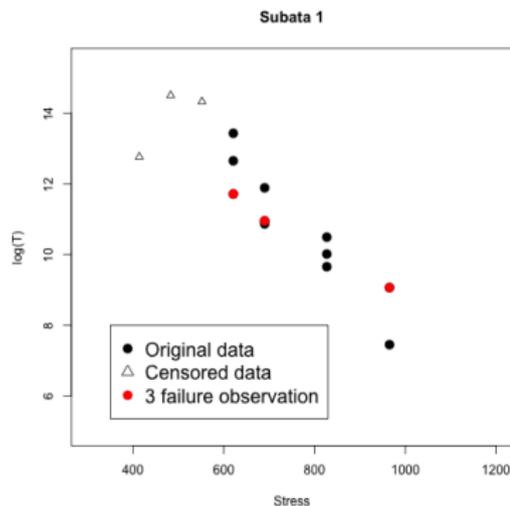
Proposed sequential Bayesian design

Let $q_L = 0.35$ and $q_U = 0.75$, and 12 new optimal design points are determined sequentially.



- The optimum stress levels can be divided into two groups: higher and lower levels.
- The proportion of higher and lower levels are 0.36 and 0.64.

Accurate estimation for small sample size?



Maximum likelihood estimators

	\hat{A}	\hat{B}	$\hat{\nu}$
$\hat{\theta}_0$	0.0157	0.3188	0.7259
$\hat{\theta}_1$	0.0005	0.7429	0.1658
$\hat{\theta}_2$	0.0162	0.3333	0.4044

Comparison I

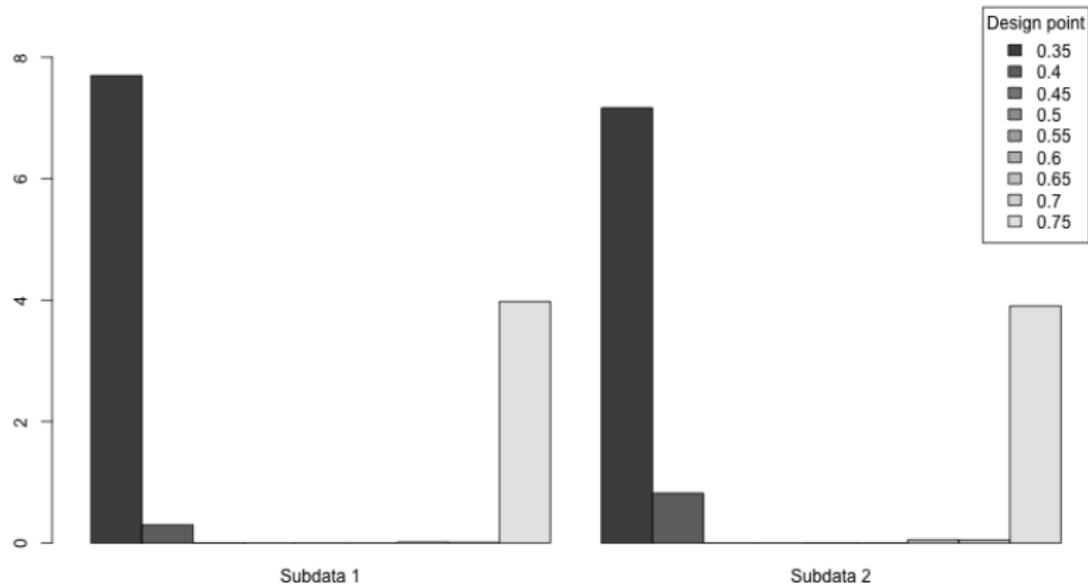
Assume the historical data is subdata 1 or subdata 2, and compare to the **two-level optimum design** (TOD, King et al. 2016).

Design	Stress levels	Sample size allocation
TOD based on $\hat{\theta}_0$	(0.35, 0.75)	(8, 4)
TOD based on $\hat{\theta}_1$	(0.65, 0.75)	(11, 1)
TOD based on $\hat{\theta}_2$	(0.35, 0.75)	(8, 4)

mean(AVar)	Subdata 1	Subdata 2
TOD by $\hat{\theta}_0$	0.6236	0.4276
Sequential Bayesian design	0.7663	0.7170
TOD by ML estimators	4.0337	0.4240

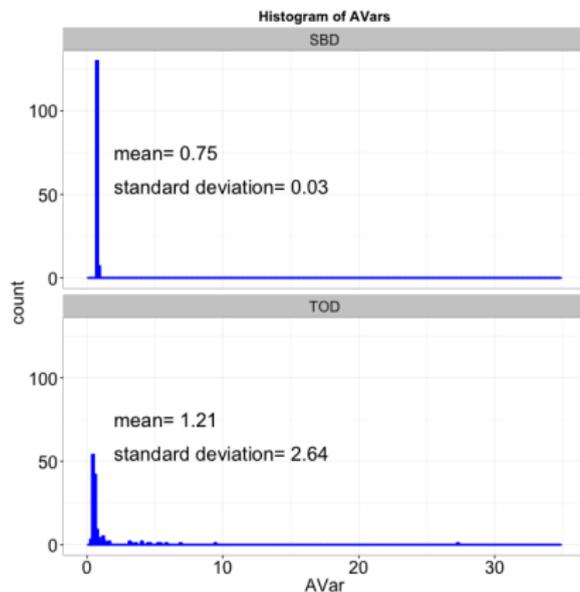
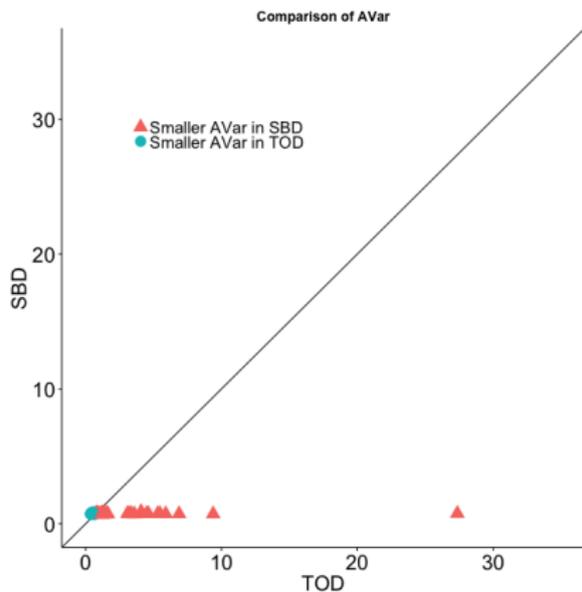
Sample size allocation

Average of sample size allocation



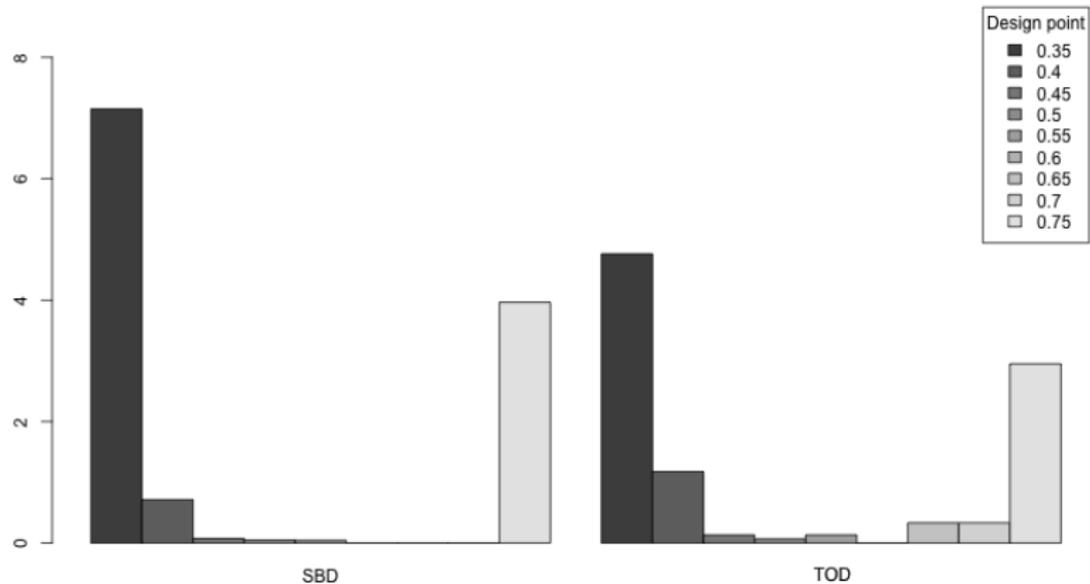
Comparison II

- Randomly taking 3 observations as the historical data, determine the traditional optimal design based on its ML estimators and the sequential Bayesian design (SBD).
- There are 165 combinations chosen in the simulation study.



Sample size allocation

Average of sample size allocation



Conclusion and Future Research

In sequential Bayesian designs,

- The optimal sequential Bayesian designs make new design points to either higher or lower stress levels.
- The sample size allocation is similar to the traditional two-level optimal design under the true values.
- The proposed method is more robust for small sample size.

Future research:

- Roy et al. (2009) proved the sequential Bayesian D-optimal design converges to the local D-optimal design for binary data.
- What are convergence properties of sequential Bayesian design for life test planning?

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- King, C., Hong, Y., DeHart, S. P., DeFeo, P. A., and Pan, R. (2016). Planning fatigue tests for polymer composites. *Journal of Quality Technology* (tentatively accepted).
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